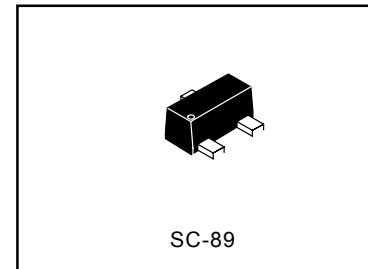


N-Channel 1.8-V (G-S) MOSFET

LSI1012XT1G

FEATURES

- TrenchFET® Power MOSFET: 1.8-V Rated
- Gate-Source ESD Protected: 2000 V
- High-Side Switching
- Low On-Resistance: 0.7 Ω
- Low Threshold: 0.8 V (typ)
- Fast Switching Speed: 10 ns

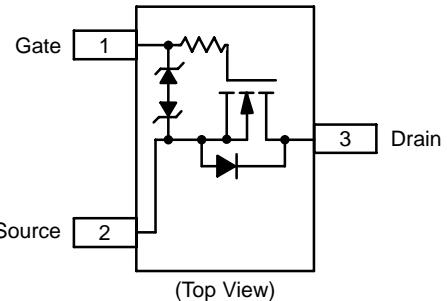
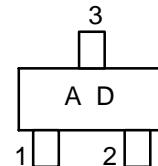


BENEFITS

- Ease in Driving Switches
- Low Offset (Error) Voltage
- Low-Voltage Operation
- High-Speed Circuits
- Low Battery Voltage Operation

APPLICATIONS

- Drivers: Relays, Solenoids, Lamps, Hammers, Displays, Memories
- Battery Operated Systems
- Power Supply Converter Circuits
- Load/Power Switching Cell Phones, Pagers


MARKING DIAGRAM


A = Specific Device Code

D = Date Code

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	5 secs	Steady State	Unit
Drain-Source Voltage	V_{DS}	20	± 6	V
Gate-Source Voltage	V_{GS}			
Continuous Drain Current ($T_J = 150^\circ\text{C}$) ^b	I_D	600	500	mA
		400	350	
Pulsed Drain Current ^a	I_{DM}	1000		mA
Continuous Source Current (diode conduction) ^b	I_S	275	250	
Maximum Power Dissipation ^b for SC-75	P_D	175	150	mW
		90	80	
Maximum Power Dissipation ^b for SC-89	P_D	275	250	
		160	140	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150		°C
Gate-Source ESD Rating (HBM, Method 3015)	ESD	2000		V

Notes

- d. Pulse width limited by maximum junction temperature.
e. Surface Mounted on FR4 Board.

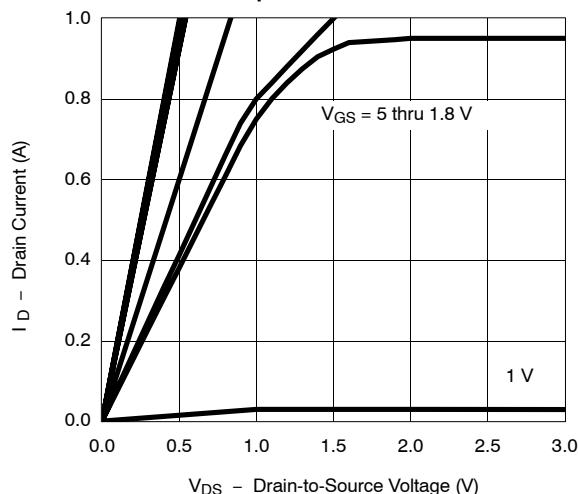
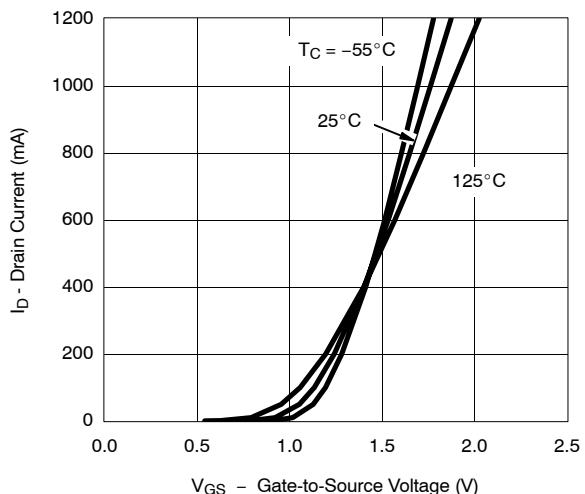
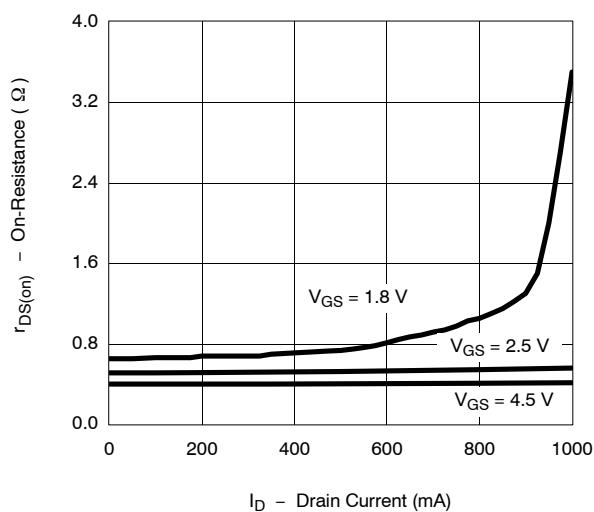
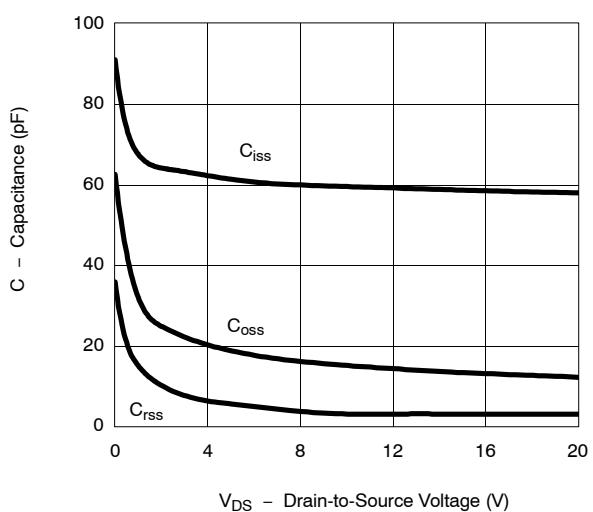
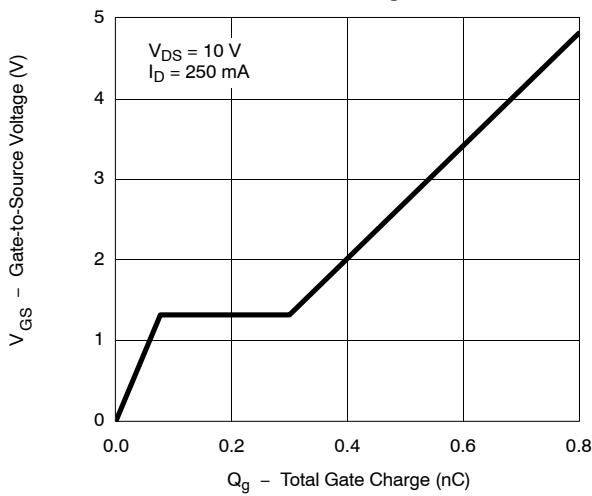
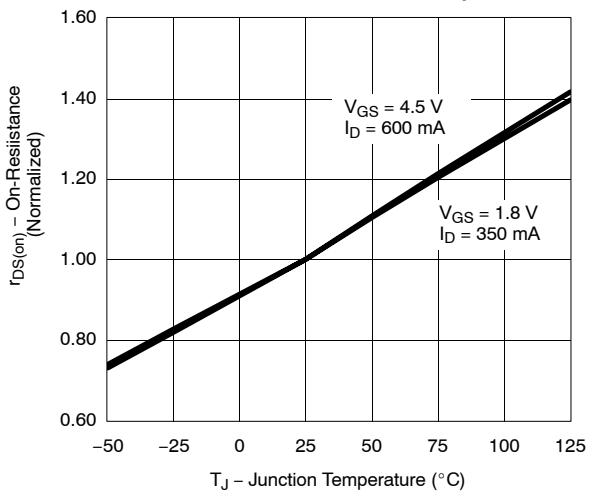
LSI1012XT1G

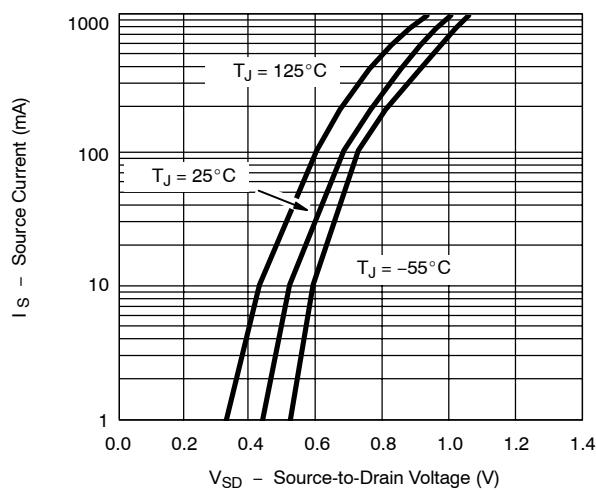
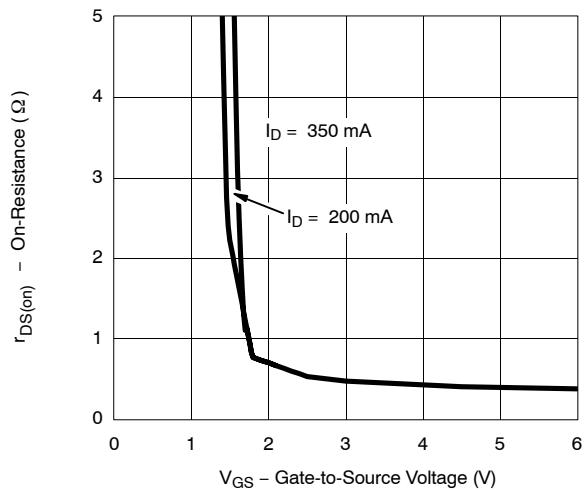
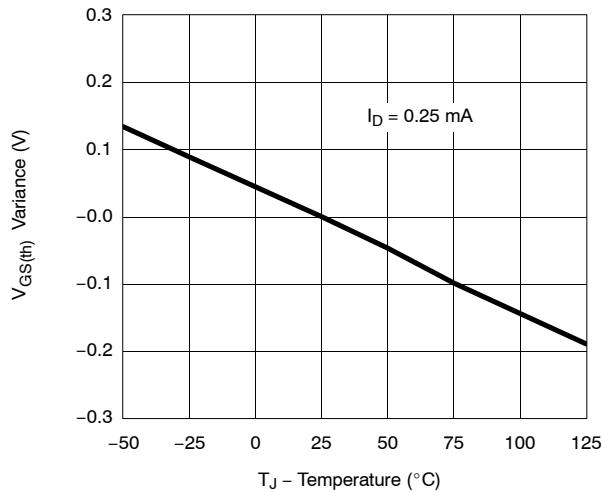
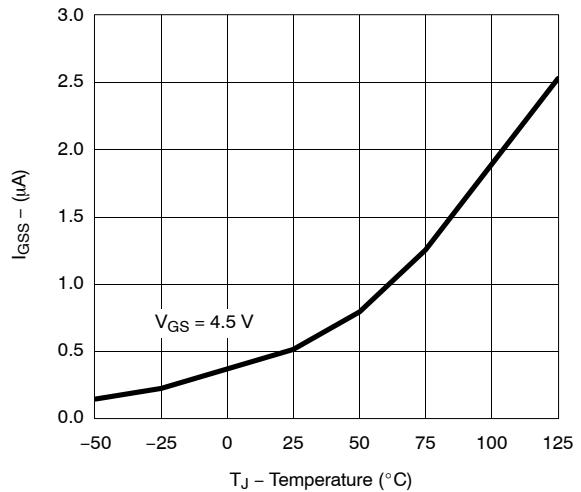
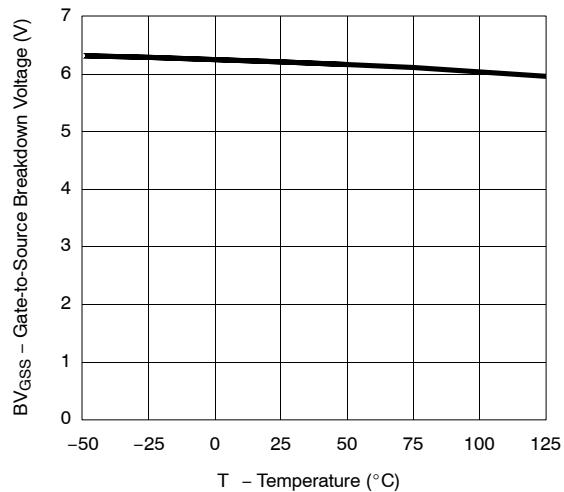
SPECIFICATIONS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)						
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.45		0.9	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$		± 0.5	± 1.0	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$		0.3	100	nA
		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 85^\circ\text{C}$			5	μA
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	700			mA
Drain-Source On-State Resistance ^a	$r_{DS(\text{on})}$	$V_{GS} = 4.5 \text{ V}, I_D = 600 \text{ mA}$		0.41	0.70	Ω
		$V_{GS} = 2.5 \text{ V}, I_D = 500 \text{ mA}$		0.53	0.85	
		$V_{GS} = 1.8 \text{ V}, I_D = 350 \text{ mA}$		0.70	1.25	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 10 \text{ V}, I_D = 400 \text{ mA}$		1.0		S
Diode Forward Voltage ^a	V_{SD}	$I_S = 150 \text{ mA}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 250 \text{ mA}$		750		pC
Gate-Source Charge	Q_{gs}			75		
Gate-Drain Charge	Q_{gd}			225		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 10 \text{ V}, R_L = 47 \Omega$ $I_D \approx 200 \text{ mA}, V_{GEN} = 4.5 \text{ V}, R_G = 10 \Omega$		5		ns
Rise Time	t_r			5		
Turn-Off Delay Time	$t_{d(\text{off})}$			25		
Fall Time	t_f			11		

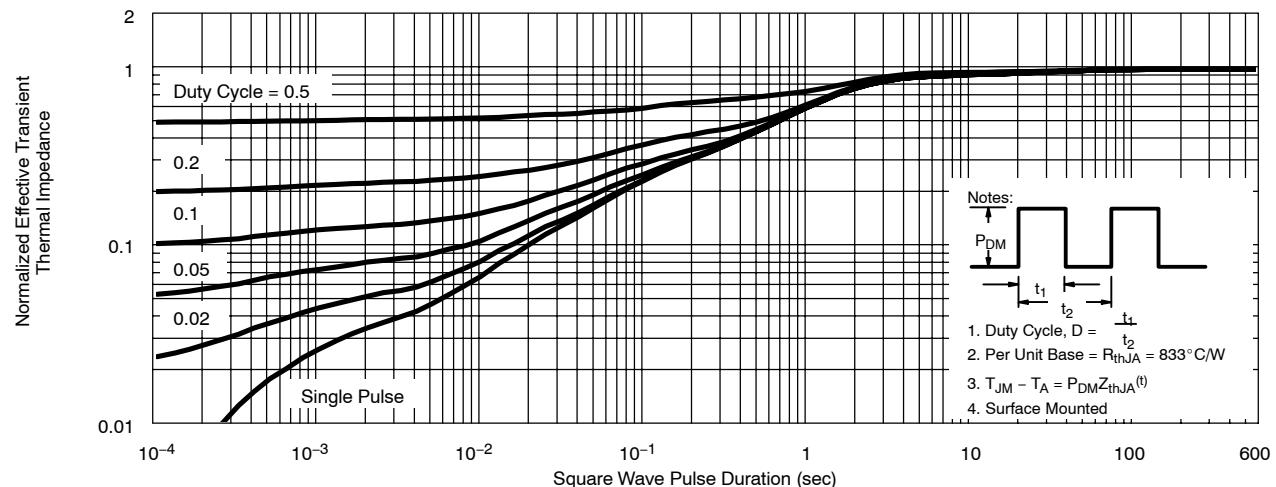
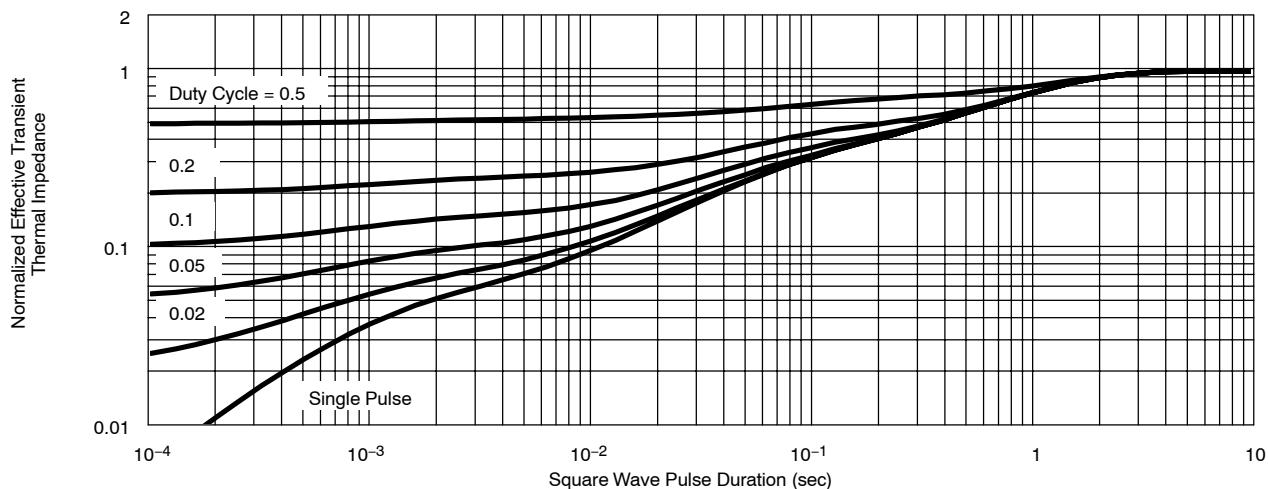
Notes

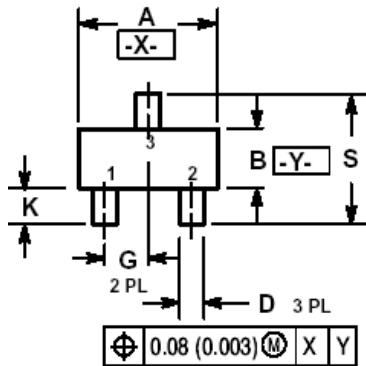
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

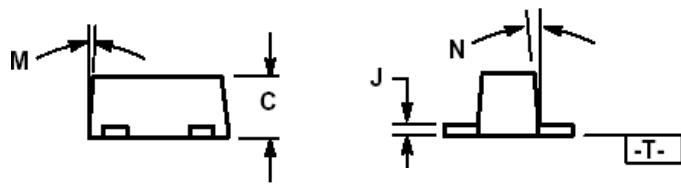
LSI1012XT1G
TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ UNLESS NOTED)
Output Characteristics

Transfer Characteristics

On-Resistance vs. Drain Current

Capacitance

Gate Charge

On-Resistance vs. Junction Temperature


LSI1012XT1G
TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ UNLESS NOTED)
Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage Variance vs. Temperature

 I_{GSS} vs. Temperature

 BV_{GSS} vs. Temperature


LSI1012XT1G
TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ UNLESS NOTED)
Normalized Thermal Transient Impedance, Junction-to-Ambient (SC-75A)

Normalized Thermal Transient Impedance, Junction-to-Foot


LSI1012XT1G
SC-89

NOTES:

- 1.DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2.CONTROLLING DIMENSION: MILLIMETERS
- 3.MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.
- 4.463C-01 OBSOLETE, NEW STANDARD 463C-02.



DIM	MILLIMETERS			INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.50	1.60	1.70	0.059	0.063	0.067
B	0.75	0.85	0.95	0.030	0.034	0.040
C	0.60	0.70	0.80	0.024	0.028	0.031
D	0.23	0.28	0.33	0.009	0.011	0.013
G	0.50 BSC			0.020 BSC		
H	0.53 REF			0.021 REF		
J	0.10	0.15	0.20	0.004	0.006	0.008
K	0.30	0.40	0.50	0.012	0.016	0.020
L	1.10 REF			0.043 REF		
M	---	---	10°	---	---	10°
N	---	---	10°	---	---	10°
S	1.50	1.60	1.70	0.059	0.063	0.067

